

Features

- N-Channel
30V/31A,
 $R_{DS(ON)} = 8m\Omega (Typ.) @ V_{GS} = 10V$
 $R_{DS(ON)} = 12m\Omega (Typ.) @ V_{GS} = 4.5V$
- P-Channel
-30V/-21A,
 $R_{DS(ON)} = 19m\Omega (Typ.) @ V_{GS} = -10V$
 $R_{DS(ON)} = 31m\Omega (Typ.) @ V_{GS} = -4.5V$
- Very low on-resistance
- Fast Switching

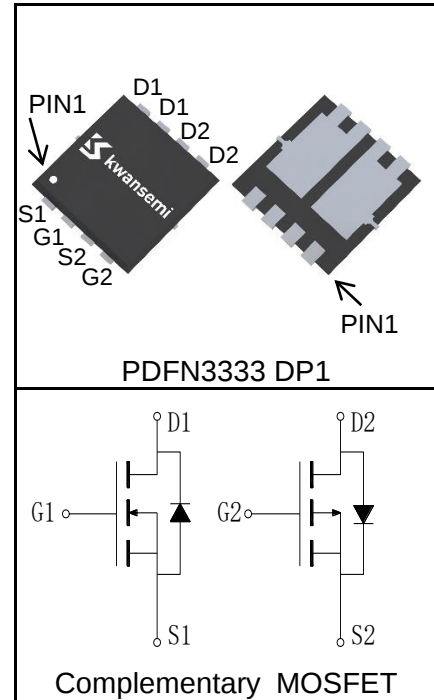
Applications

- Motor Drive Applications



Halogen-Free

Pin Description



Absolute Maximum Ratings

Symbol	Parameter		N-Channel	P-Channel	Unit
Common Ratings (T _A =25°C Unless Otherwise Noted)					
V _{DSS}	Drain-Source Voltage		30	-30	V
V _{GSS}	Gate-Source Voltage		±20	±20	
T _J	Maximum Junction Temperature		150	150	°C
T _{STG}	Storage Temperature Range		-55 to 150	-55 to 150	°C
I _S	Diode Continuous Forward Current	T _C =25°C	31	-21	A
Mounted on Large Heat Sink					
I _{DP} ^①	300μs Pulse Drain Current Tested	T _C =25°C	124	-84	A
I _D ^②	Continuous Drain Current@T _C (V _{GS} =±10V)	T _C =25°C	31	-21	A
		T _C =100°C	20	-13	
	Continuous Drain Current@T _A (V _{GS} =±10V) ^③	T _A =25°C	13	-8	
		T _A =70°C	10	-7	
P _D	Maximum Power Dissipation@T _C	T _C =25°C	16	18	W
		T _C =100°C	6.4	7.4	
	Maximum Power Dissipation@T _A ^③	T _A =25°C	2.8	2.8	
		T _A =70°C	1.8	1.8	
R _{θJC}	Thermal Resistance-Junction to Case		7.8	6.8	°C/W
R _{θJA} ^③	Thermal Resistance-Junction to Ambient		45	45	°C/W
Drain-Source Avalanche Ratings					
E _{AS} ^④	Avalanche Energy, Single Pulsed		12	16	mJ

Electrical Characteristics ($T_A=25^{\circ}\text{C}$ Unless Otherwise Noted)

Symbol	Parameter	Test Condition	KS3628MAT			Unit	
			Min.	Typ.	Max.		
Static Characteristics							
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _{DS} =250μA	N	30			V
		V _{GS} =0V, I _{DS} =-250μA	P	-30			
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =30V, V _{GS} =0V	N			1	μA
				T _J =125°C			
		V _{DS} =-30V, V _{GS} =0V	P			-1	
				T _J =125°C			
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _{DS} =250μA	N	1.1	1.7	2.1	V
		V _{DS} =V _{GS} , I _{DS} =-250μA	P	-1.1	-1.7	-2.1	
I _{GSS}	Gate Leakage Current	V _{GS} =±20V, V _{DS} =0V	N			±100	nA
		V _{GS} =±20V, V _{DS} =0V	P			±100	
R _{DS(ON)} ⑤	Drain-Source On-state Resistance	V _{GS} =10V, I _{DS} =12A	N		8	9.5	mΩ
		V _{GS} =-10V, I _{DS} =-12A	P		19	24	
		V _{GS} =4.5V, I _{DS} =10A	N		12	16	
		V _{GS} =-4.5V, I _{DS} =-10A	P		31	41	
Diode Characteristics							
V _{SD} ⑤	Diode Forward Voltage	I _{SD} =12A, V _{GS} =0V	N		0.85	1.2	V
		I _{SD} =-12A, V _{GS} =0V	P		-0.92	-1.2	
t _{rr}	Reverse Recovery Time	N-Channel I _{SD} =8A, dI _{SD} /dt=100A/μs	N		12		ns
			P		16		
Q _{rr}	Reverse Recovery Charge	P-Channel I _{SD} =-8A, dI _{SD} /dt=100A/μs	N		21		nC
			P		28		
Dynamic Characteristics ⑥							
R _G	Gate Resistance	V _{GS} =0V, V _{DS} =0V, F=1MHz	N		0.8		Ω
			P		4.5		
C _{iss}	Input Capacitance	N-Channel V _{GS} =0V, V _{DS} =15V, Frequency=1.0MHz	N		555		pF
			P		1240		
C _{oss}	Output Capacitance		N		260		
			P		205		
C _{rss}	Reverse Transfer Capacitance	P-Channel V _{GS} =0V, V _{DS} =-15V, Frequency=1.0MHz	N		25		
			P		120		

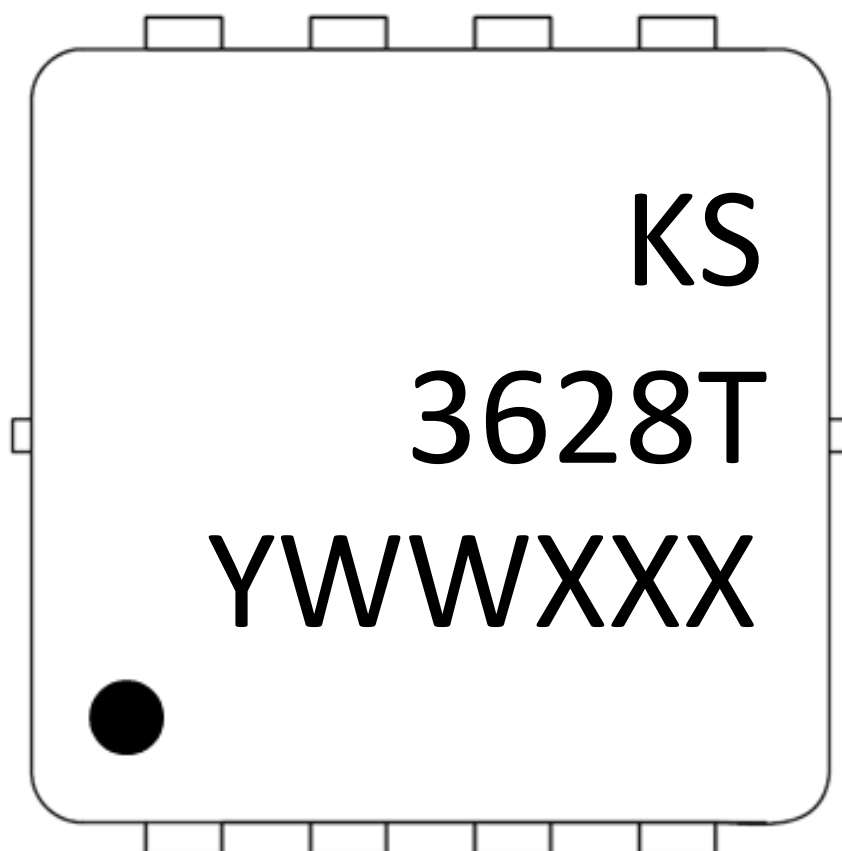
Electrical Characteristics ($T_A=25^{\circ}\text{C}$ Unless Otherwise Noted)

Symbol	Parameter	Test Condition	KS3628MAT			Unit
			Min.	Typ.	Max.	
Dynamic Characteristics ^⑥						
t _{d(ON)}	Turn-on Delay Time	N-Channel V _{DD} =15V, I _{DS} =12A, V _{GEN} =10V, R _G =3Ω	N		8	ns
t _r	Turn-on Rise Time		P		13	
			N		10	
t _{d(OFF)}	Turn-off Delay Time		P		25	
		N		12		
t _f	Turn-off Fall Time	P		38		
		N		5		
		P		14		
Gate Charge Characteristics ^⑥						
Q _g	Total Gate Charge	N-Channel V _{DS} =15V, V _{GS} =10V, I _{DS} =12A	N		4.8	nC
Q _{gs}	Gate-Source Charge		P		21	
		N		2.3		
Q _{gd}	Gate-Drain Charge	P		6		
		N		1.4		
		P		5		

- Notes:
- ① Pulse width limited by safe operating area.
 - ② Calculated continuous current based on maximum allowable junction temperature.
 - ③ When mounted on 1 inch square copper board, $t \leq 10\text{sec}$. The value in any given application depends on the user's specific board design.
 - ④ Limited by T_{Jmax} . Starting $T_J = 25^{\circ}\text{C}$, N Channel: $L = 0.5\text{mH}$, $R_G = 25\Omega$, $I_{AS} = 7\text{A}$, $V_{GS} = 10\text{V}$, P-Channel: $L = 0.5\text{mH}$, $R_G = 25\Omega$, $I_{AS} = -8\text{A}$, $V_{GS} = -10\text{V}$, 100% tested and guaranteed.
 - ⑤ Pulse test; Pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$.
 - ⑥ Guaranteed by design, not subject to production testing.

Ordering and Marking Information

Device	Package	Packaging	Quantity	Reel Size	Tape width
KS3628MAT	PDFN3333 DP1	Tape&Reel	5000	13"	12mm

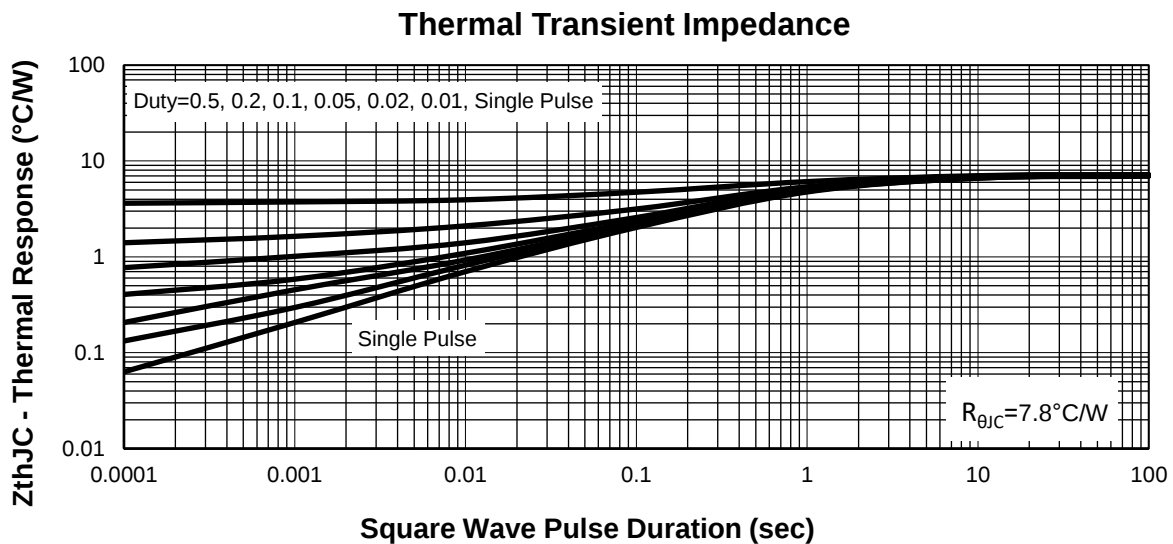
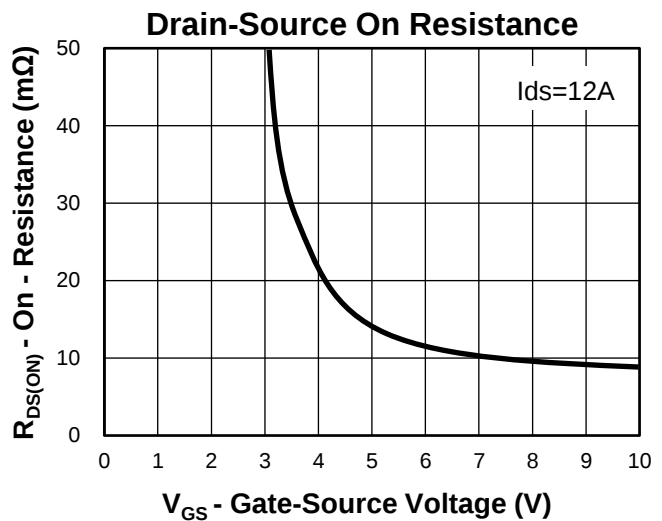
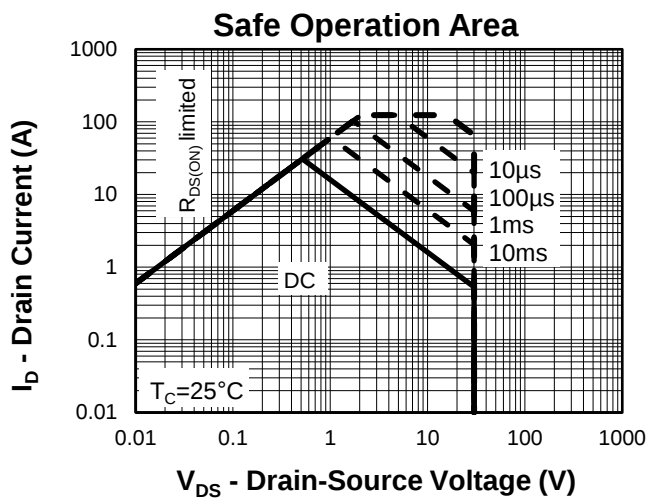
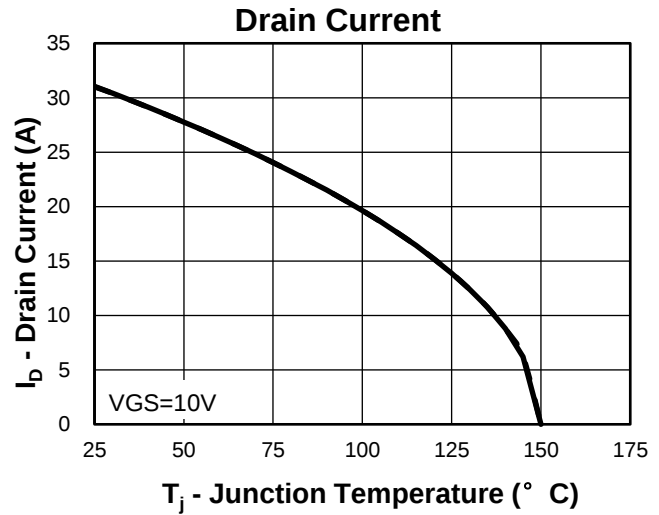
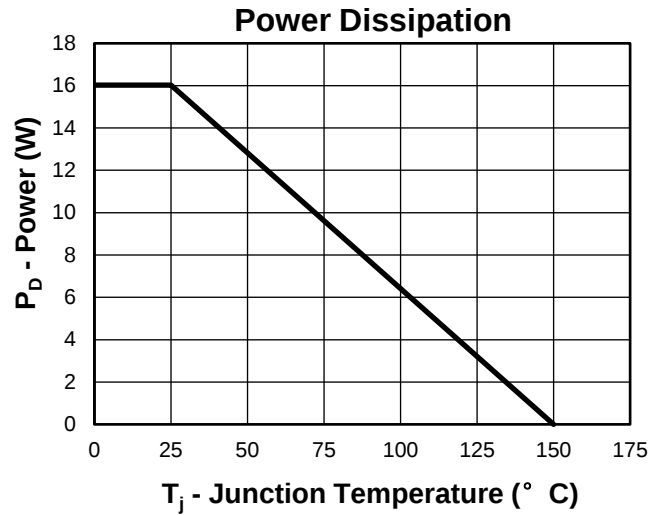


1st Line: Kwansemi Code(KS)

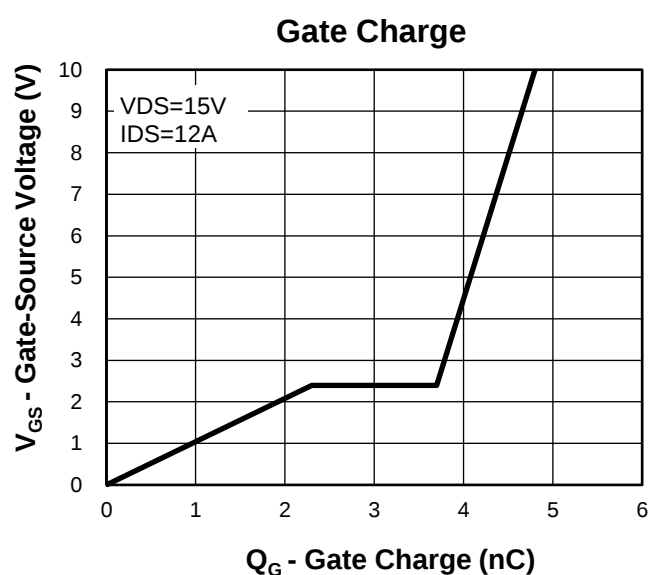
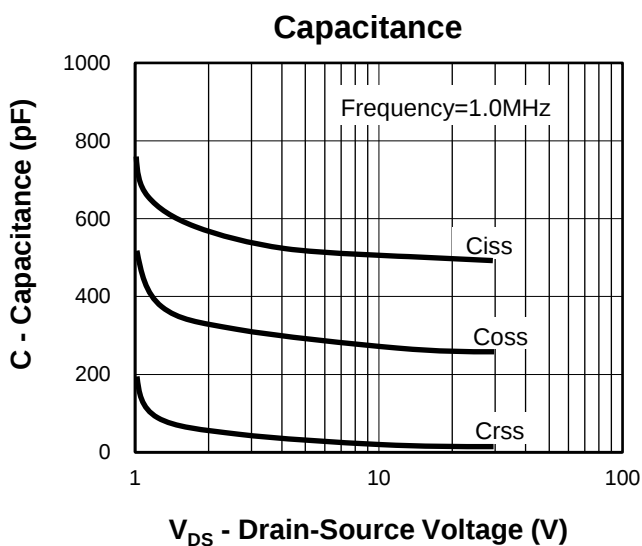
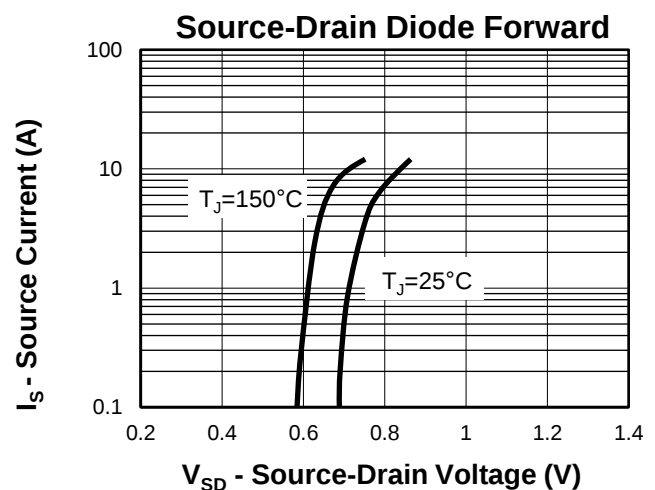
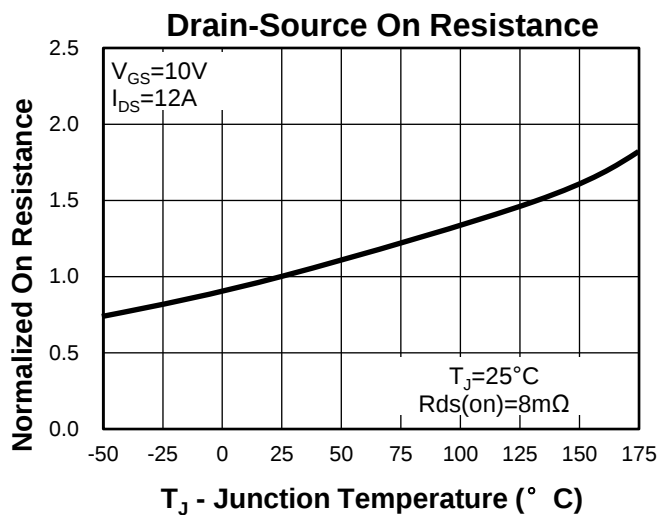
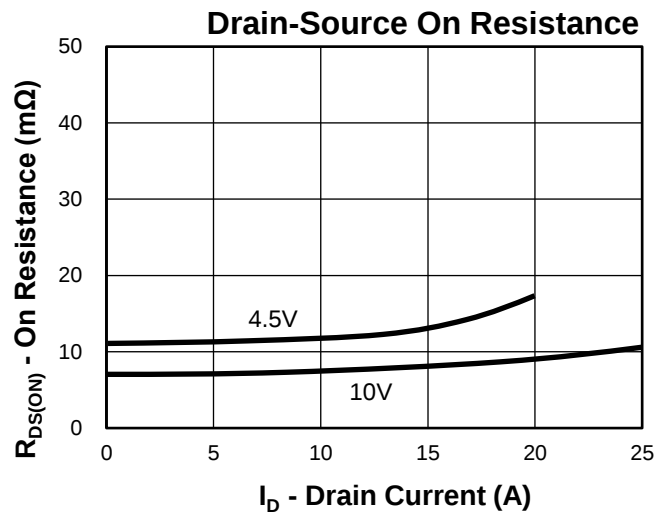
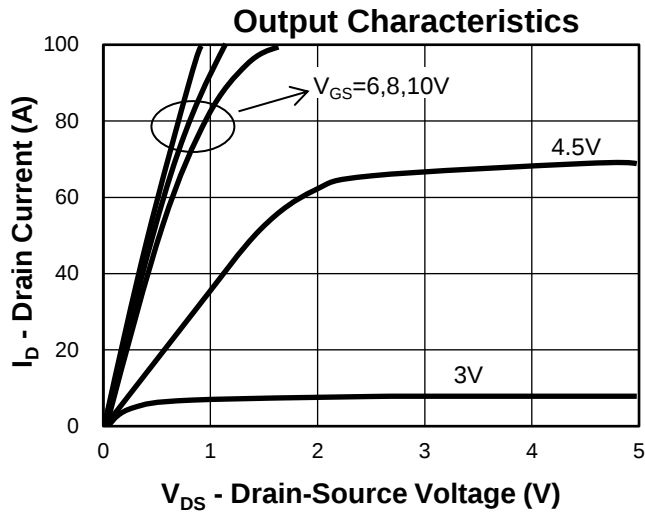
2nd Line: Part Number(3628T)

3rd Line: Lot Number(YWWXXX)

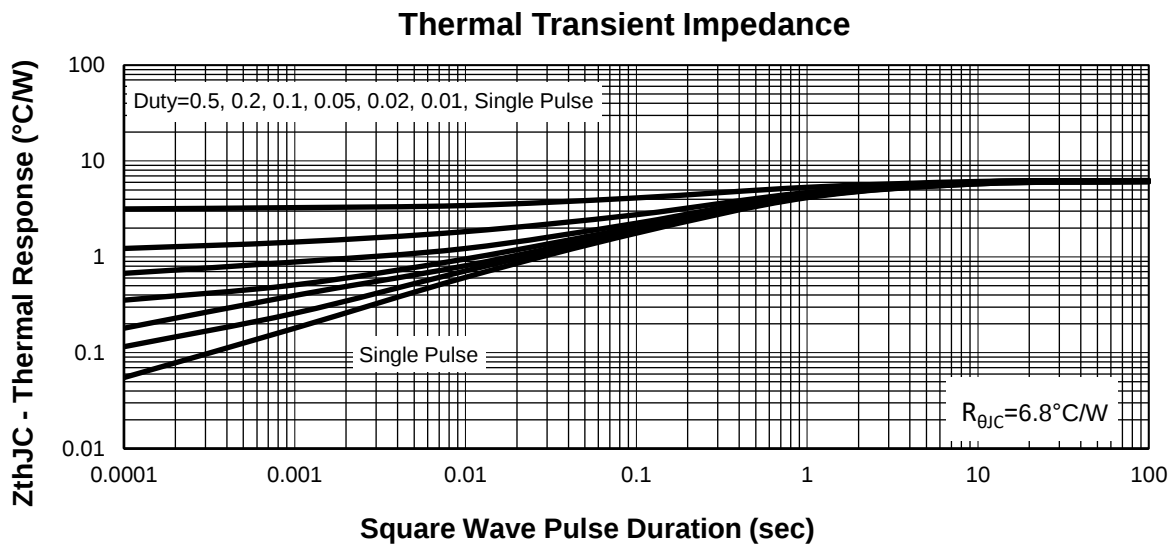
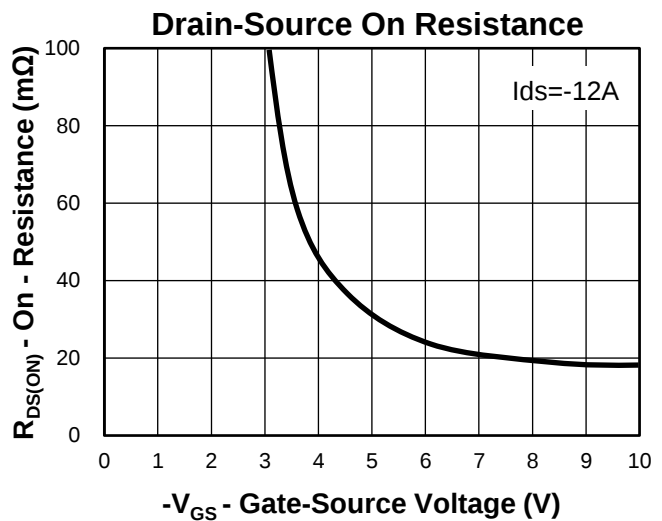
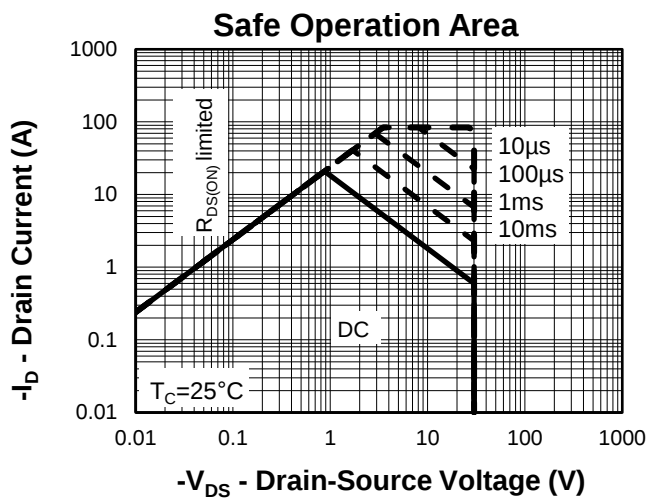
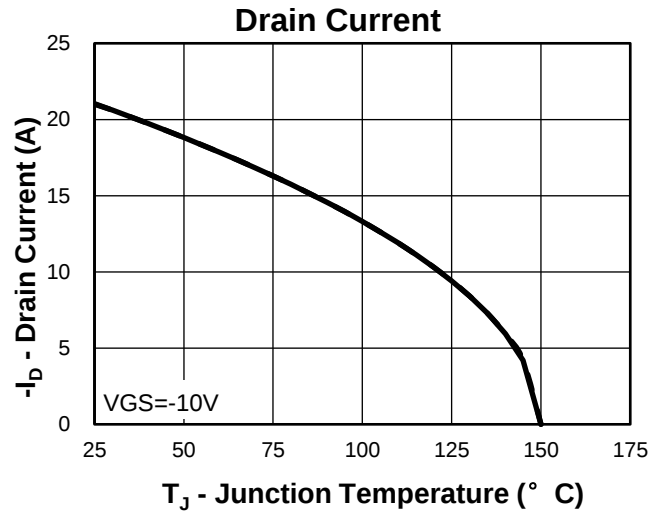
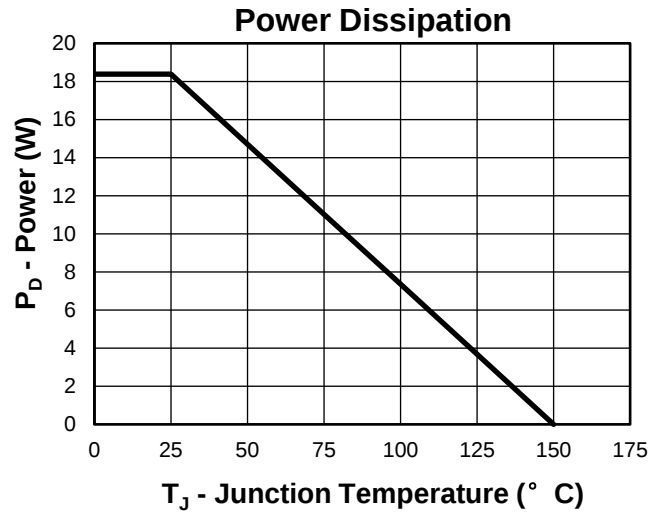
Typical Characteristics(N-Channel)



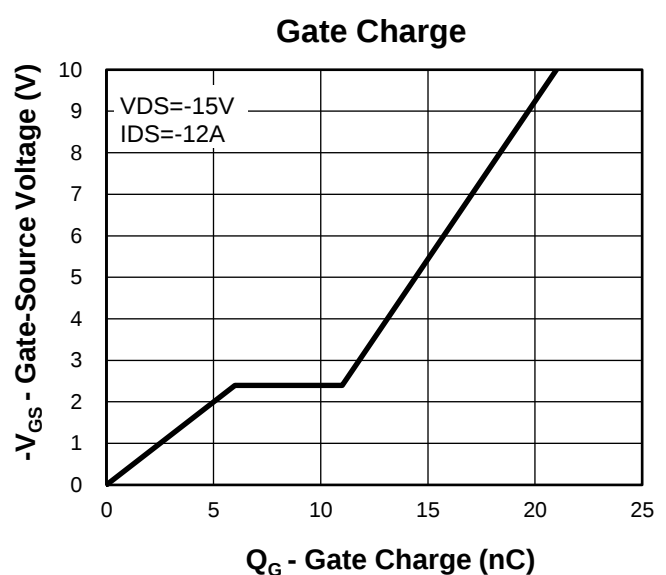
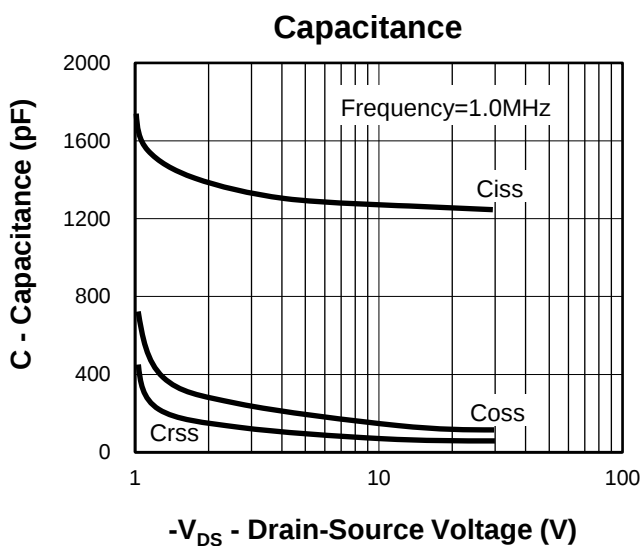
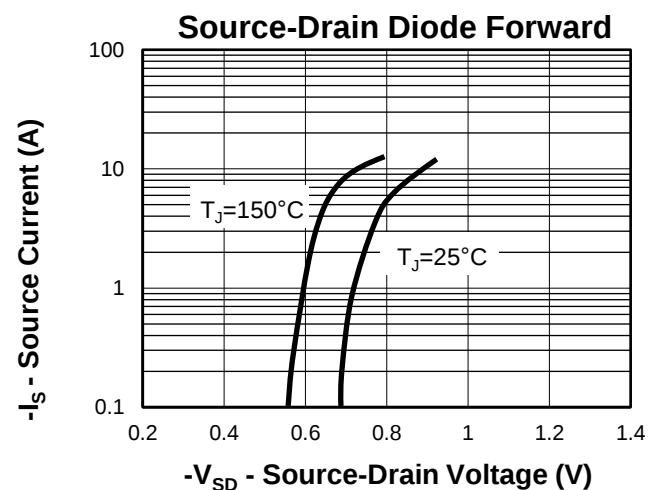
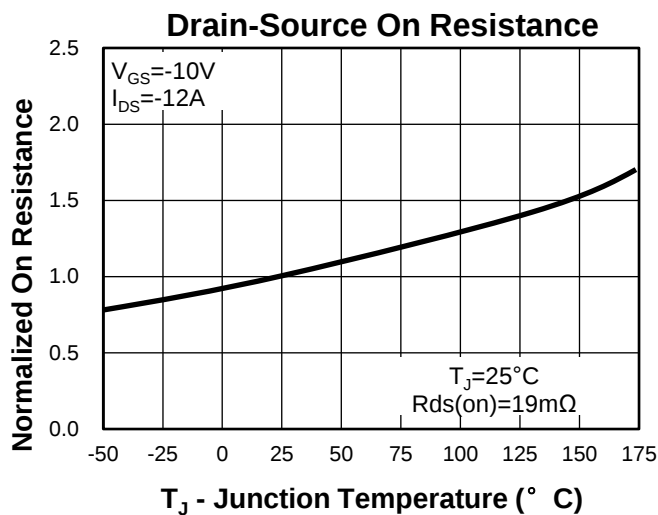
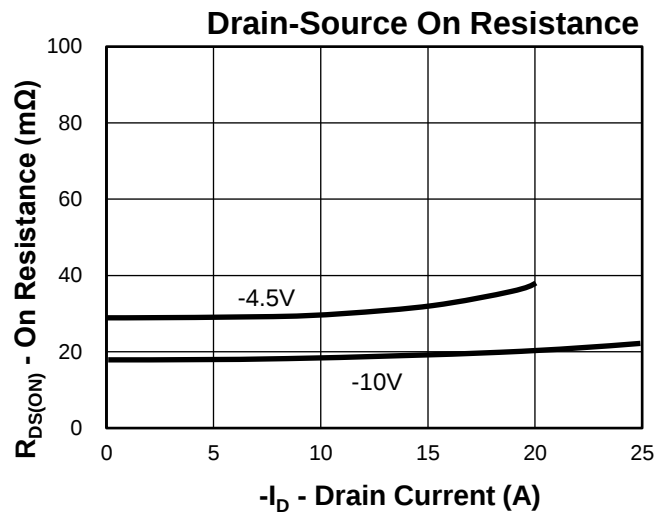
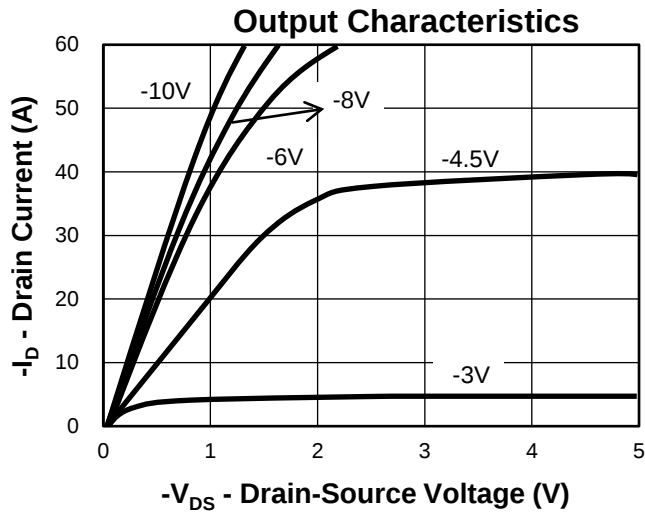
Typical Characteristics(N-Channel)

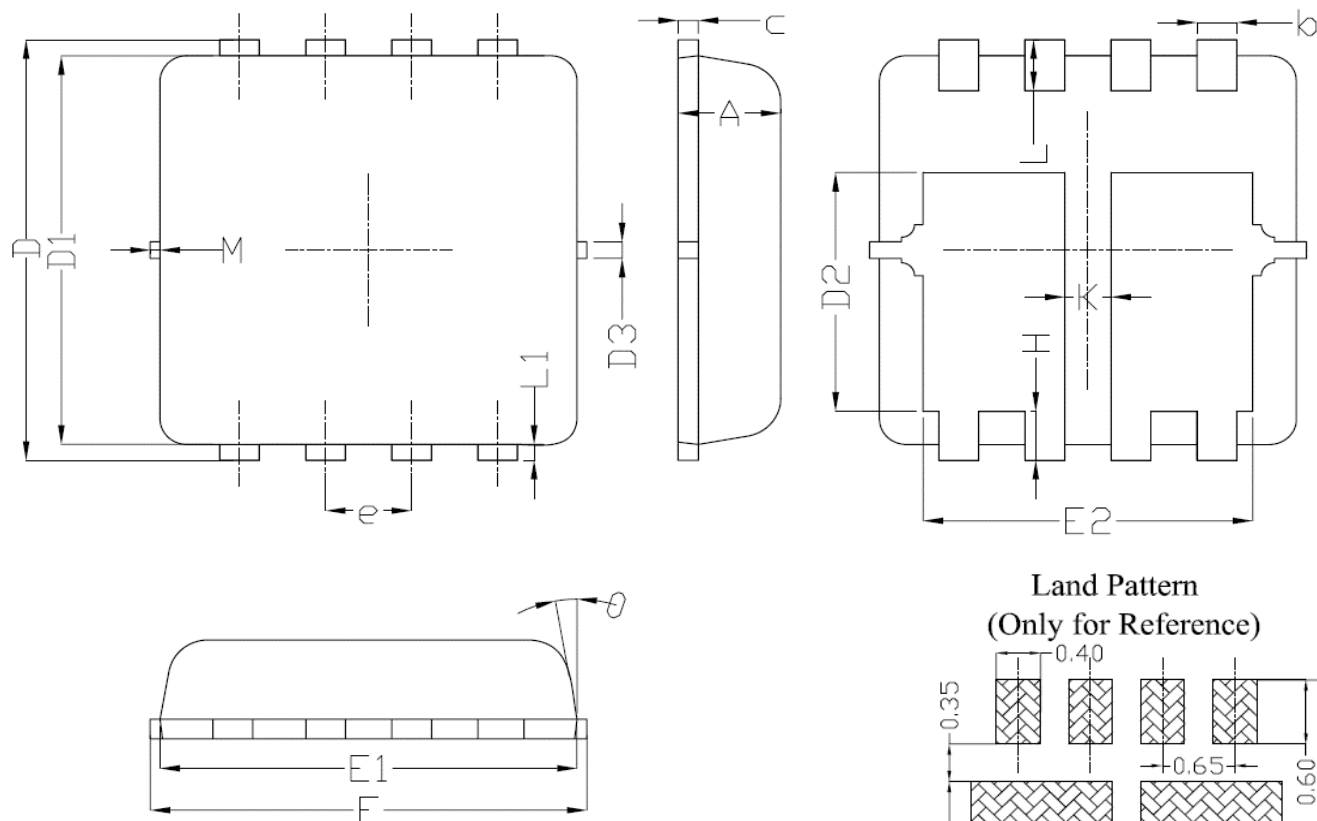


Typical Characteristics(P-Channel)



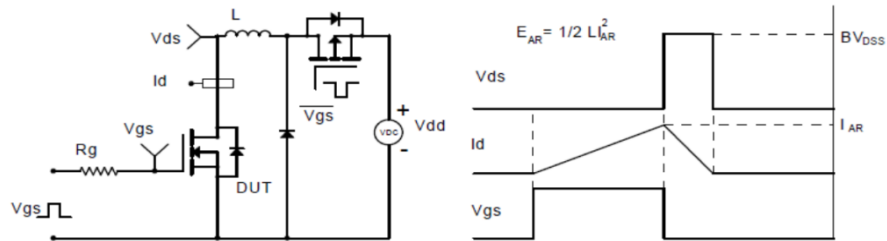
Typical Characteristics(P-Channel)



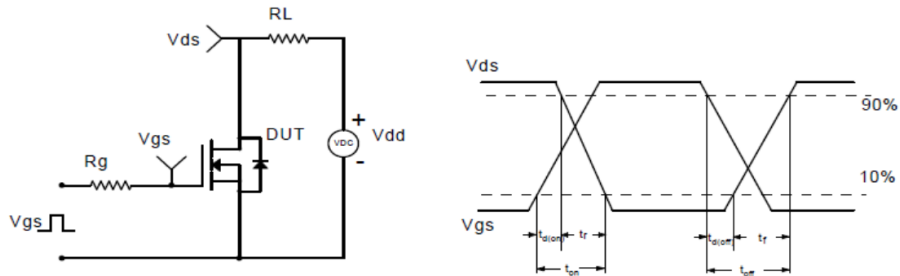
Package Information
PDFN3333 DP1


SYMBOL	MM			INCH		
	MIN	NOM	MAX	MIN	NOM	MAX
A	0.70	0.75	0.80	0.028	0.030	0.031
b	0.25	0.30	0.35	0.010	0.012	0.014
c	0.10	0.15	0.25	0.004	0.006	0.010
D	3.25	3.35	3.45	0.128	0.132	0.136
D1	3.00	3.10	3.20	0.118	0.122	0.126
D2	1.78	1.88	1.98	0.070	0.074	0.078
D3		0.13			0.005	
E	3.20	3.30	3.40	0.126	0.130	0.134
E1	3.00	3.15	3.20	0.118	0.124	0.126
E2	2.39	2.49	2.59	0.094	0.098	0.102
e	0.65 BSC			0.026 BSC		
H	0.30	0.39	0.50	0.012	0.015	0.020
L	0.30	0.40	0.50	0.012	0.016	0.020
L1		0.13			0.005	
K	0.30			0.012		
θ	0°		12°	0°		12°
M			0.15			0.006

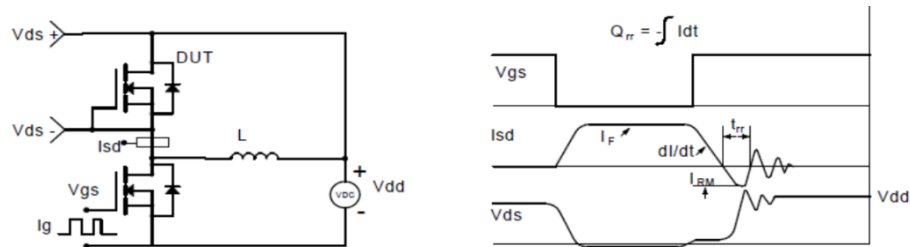
Avalanche Test Circuit and Waveforms(N-Channel)



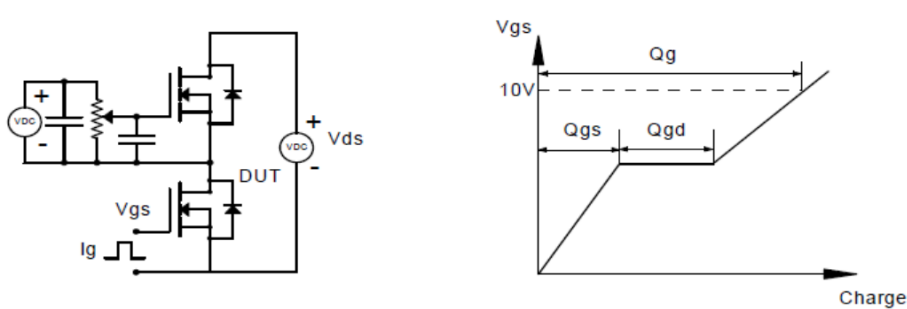
Switching Time Test Circuit and Waveforms(N-Channel)



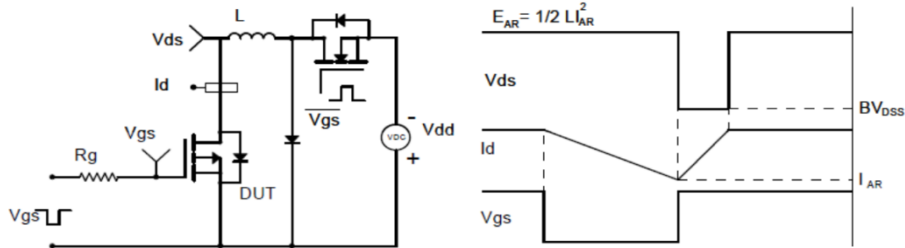
Diode Recovery Test Circuit and Waveforms(N-Channel)



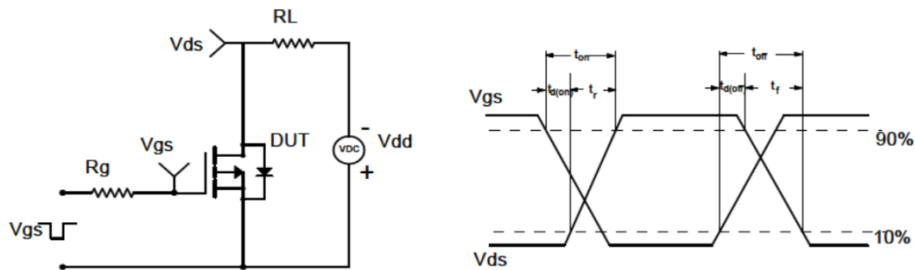
Gate Charge Test Circuit and Waveform(N-Channel)



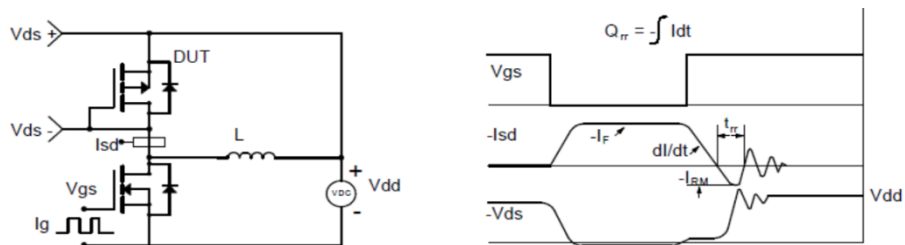
Avalanche Test Circuit and Waveforms(P-Channel)



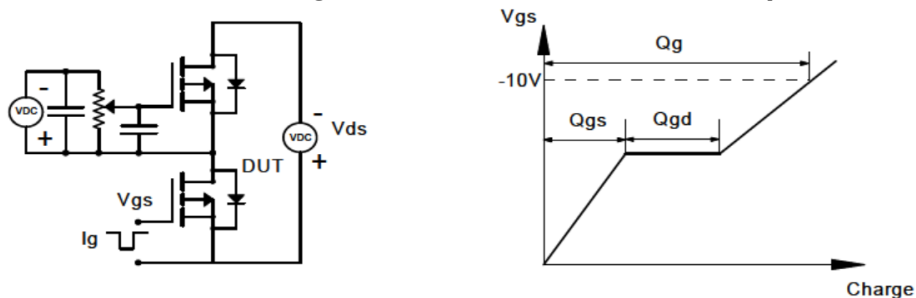
Switching Time Test Circuit and Waveforms(P-Channel)



Diode Recovery Test Circuit and Waveforms(P-Channel)



Gate Charge Test Circuit and Waveform(P-Channel)



Customer Service

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